

09954809_CLS

Most Frequently Occurring Classifications of Patents Returned
From A Search of 09954809 on September 30, 2003

Original Classifications

7 324/765
5 324/601
3 327/108
3 365/230.05
3 714/736
2 702/85
2 714/726
2 714/727
2 714/740

Cross-Reference Classifications

4 324/638
3 324/158.1
3 324/601
3 324/763
3 714/724
2 324/637
2 326/30
2 326/90
2 327/563
2 327/68
2 356/364
2 365/200
2 365/201
2 365/230.05
2 713/500
2 714/727

PLW's
Report

Combined Classifications

8 324/601
7 324/765
5 324/638
5 365/230.05
4 324/158.1
4 714/724
4 714/727
4 714/736
3 324/637
3 324/763
3 327/108
3 365/201
3 702/85
2 324/627

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2 326/30
2 326/90
2 327/563
2 327/68
2 356/364
2 356/73.1
2 365/189.04
2 365/200
2 702/76
2 713/500
2 714/726
2 714/740

09954809_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09954809 on September 30, 2003

8 324/601 (5 OR, 3 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
 324/601 RELATIONSHIPS
 .Calibration

7 324/765 (7 OR, 0 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .Of individual circuit component or element
 324/765 ..Test of semiconductor device

5 324/638 (1 OR, 4 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
 324/629 RELATIONSHIPS
 .Distributive type parameters
 324/637 ..Using transmitted or reflected microwaves
 324/638 ...Scattering type parameters (e.g., complex
 reflection coefficient)

5 365/230.05 (3 OR, 2 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/230.01 ADDRESSING
 365/230.05 .Multiple port access

4 324/158.1 (1 OR, 3 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/158.1 MISCELLANEOUS

4 714/724 (1 OR, 3 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing

4 714/727 (2 OR, 2 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT

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DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
n design (LSSD))
714/727 ...Boundary scan

4 714/736 (3 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/736 ..Device response compared to expected
fault-free response

3 324/637 (1 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
RELATIONSHIPS
324/629 .Distributive type parameters
324/637 ..Using transmitted or reflected microwaves

3 324/763 (0 OR, 3 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/763 ..DUT including test circuit

3 327/108 (3 OR, 0 XR)
Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
DEVICES, CIRCUITS, AND SYSTEMS
327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING
327/108 .Current driver

3 365/201 (1 OR, 2 XR)
Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01 READ/WRITE CIRCUIT
365/201 .Testing

3 702/85 (2 OR, 1 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/85 CALIBRATION OR CORRECTION SYSTEM

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2 324/627 (1 OR, 1 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
 REPRESENTATIVE OF ELECTRICAL STIMULUS/RES
 PONSE
 RELATIONSHIPS
 324/612 .Parameter related to the reproduction or
 fidelity of a signal affected by a circuit
 under test
 324/627 ..Shielding effectiveness (SE)

2 326/30 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/21 SIGNAL SENSITIVITY OR TRANSMISSION INTEGRITY
 326/30 .Bus or line termination (e.g., clamping,
 impedance matching, etc.)

2 326/90 (0 OR, 2 XR)
 Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
 326/62 INTERFACE (E.G., CURRENT DRIVE, LEVEL SHIFT,
 ETC.)
 326/82 .Current driving (e.g., fan in/out, off chip
 driving, etc.)
 326/89 ..Bipolar transistor
 326/90 ...Bus driving

2 327/563 (0 OR, 2 XR)
 Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
 DEVICES, CIRCUITS, AND SYSTEMS
 327/524 SPECIFIC IDENTIFIABLE DEVICE, CIRCUIT, OR
 SYSTEM
 327/560 .Nonlinear amplifying circuit
 327/563 ..With differential amplifier

2 327/68 (0 OR, 2 XR)
 Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
 DEVICES, CIRCUITS, AND SYSTEMS
 327/1 SPECIFIC SIGNAL DISCRIMINATING (E.G.,
 COMPARING, SELECTING, ETC.) WITHOUT SUBS
 EQUENT CONTROL
 327/50 .By amplitude
 327/63 ..Comparison between plural varying inputs
 327/68 ...Input provides varying reference signal

2 356/364 (0 OR, 2 XR)
 Class 356 : OPTICS: MEASURING AND TESTING
 356/364 BY POLARIZED LIGHT EXAMINATION

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- 2 356/73.1 (1 OR, 1 XR)
 Class 356 : OPTICS: MEASURING AND TESTING
 356/73.1 FOR OPTICAL FIBER OR WAVEGUIDE INSPECTION
- 2 365/189.04 (1 OR, 1 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/189.01 READ/WRITE CIRCUIT
 365/189.04 .Simultaneous operations (e.g., read/write)
- 2 365/200 (0 OR, 2 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/189.01 READ/WRITE CIRCUIT
 365/200 .Bad bit
- 2 702/76 (1 OR, 1 XR)
 Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
 TESTING
 702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
 702/57 .Electrical signal parameter measurement syste
 m
 702/66 ..Waveform analysis
 702/75 ...Frequency
 702/76Frequency spectrum
- 2 713/500 (0 OR, 2 XR)
 Class 713 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING
 SYSTEMS: SUPPORT
 713/500 CLOCK, PULSE, OR TIMING SIGNAL GENERATION OR
 ANALYSIS
- 2 714/726 (2 OR, 0 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/726 ..Scan path testing (e.g., level sensitive sca
 n
 design (LSSD))
- 2 714/740 (2 OR, 0 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/738 ..Including test pattern generator
 714/740 ...Having analog signal

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6614237	90
6407542	85
6177804	76
4775977	73
6087843	69
5307284	67
6060888	67
6396285	67
6417674	67
6571187	67
5793213	66
5260947	63
5996102	62
5999008	61
6194911	61
5942922	59
6057716	59
5930735	59
6016566	59
6028438	59
6356096	59
6163223	59
5668819	59
5831440	59
6256760	59
6260166	59
6397354	59
6446230	59
6449033	59
6529844	59
6606158	59
5734613	57
5742557	57
5896330	57
6232815	57
5982827	56
5673275	56
5233564	55
4808913	54
5430400	54
6166569	54
6188227	54
6281699	54
6329833	54
6380533	54
6414496	54
6421624	54
6052810	54

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5818243 54
5561638 53